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**NATIONAL STANDARD OF THE
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GB/T 33523.603-2022

**Geometrical product specifications (GPS) - Surface texture:
Areal - Part 603: Nominal characteristics of non-contact
(phase-shifting interferometric microscopy) instruments**

产品几何技术规范（GPS）表面结构 区域法 第603部分：非接触（相移干涉显微）式仪器的标称特性

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Foreword

This document was issued on 30 December 2022 by the State Administration for Market Regulation; Standardization Administration of the PRC and takes effect on 1 April 2023.

It is a GB/T standard: recommended rather than compulsory, but it is the text a Chinese reviewer applies when assessing a submission.

It is classified under ICS 17.040.20, Chinese classification J04.

This document is in accordance with the provisions of GB/T 1.1-2020 "Guidelines for Standardization Work Part 1. Structure and Drafting Rules for Standardization Documents" drafting.

This document is part 603 of GB/T 33523 "Geometric Specification for Products (GPS) Surface Structure Area Law". GB/T 33523

The following parts have been published.

- Part 1. Representation of surface structure;
- Part 2. Terms, definitions and surface structure parameters;
- Part 3. Specification operation set;
- Part 6. Classification of surface structure measurement methods;
- Part 70. Physical measurement standards;
- Part 71. Software measurement standards;

- Part 72.XML file format x3p;
- Part 601.Nominal characteristics of contact (stylus) instruments;
- Part 602.Nominal characteristics of non-contact (confocal chromatic aberration probe) instruments;
- Part 603.Nominal characteristics of non-contact (phase-shift interference microscopy) instruments;
- Part 604.Nominal characteristics of non-contact (coherent scanning interference) instruments;
- Part 605.Nominal characteristics of non-contact (point autofocus probe) instruments;
- Part 606.Nominal characteristics of non-contact (zoom) instruments;
- Part 701.Calibration and measurement standards for contact (stylus) instruments.

This document is equivalent to ISO 25178-603.2013 "Product Geometric Specifications (GPS) Surface Structure Area Law Part 603

Part. Nominal Characteristics of Non-Contact (Phase Shift Interference Microscopy) Instruments".

This document adds a chapter "Normative References".

Please note that some contents of this document may refer to patents. The issuing agency of this document assumes no responsibility for identifying patents.

This document is proposed and managed by the National Product Geometric Technical Specification Standardization Technical Committee (SAC/TC240).

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Introduction

With the implementation of the national product quality improvement plan, the unified norms or principles used in the process of product design, manufacturing, measurement and inspection

needs are becoming more and more urgent. The surface structure representation method and related standards in the original product geometric technical specifications can no longer meet the requirements of the product manufacturing process.

Surface quality control requirements in the process.

GB/T 33523 "Product Geometric Specifications (GPS) Surface Structure Area Method" is based on the new generation of GPS product geometric specifications

Through digital measurement technology, software analysis technology and measurement evaluation, a new set of three-dimensional surface structure measurement and analysis recommended national standards. GB/T 33523, on the basis of proposing the surface structure representation, surface structure parameters and standard operation set, analyzes

The method of surface structure measurement is given, the measurement technique used and the nominal characteristics of the instrument are given. In particular, GB/T 33523 covers contact

At the same time, it focuses on introducing a variety of non-contact measuring instruments that are of great value in high-precision measurement applications but lack standard support.

Measuring instrument. The standard also regulates physical measurement and software measurement standards, and gives software file standards and metrological characteristics of surface structure measurement.

GB/T 33523 realizes the leap from two-dimensional profile measurement to three-dimensional surface structure measurement, and provides a design basis for the GPS product geometric specification system.

Quantitative test support.

GB/T 33523 is proposed to consist of 14 parts.

--- Part 1. Representation of surface structure. The purpose is to specify the product technical documents (such as drawings, specifications, contracts and reports)

Rules for representing the surface structure of a region using graphical symbols.

--- Part 2. Terms, definitions and surface structure parameters. The purpose of this document is to specify the terms, definitions and parameter.

--- Part 3. Specification operation set. The purpose is to provide complete rules applicable to the evaluation of surface structure (scale-limited surface) by the regional method.

Fan operation set.

--- Part 6. Classification of surface structure measurement methods. The purpose is to define a classification system mainly for methods of surface texture measurement,

Define three types of methods, describe the relationship between the three types of methods, and give a brief description of the specific methods.

--- Part 70. physical measurement standards. The purpose is to define a practice for the periodic verification and adjustment of area-based surface structure measurement instruments.

properties of physical measurement standards.

--- Part 71. Software measurement standards. The purpose is to specify the S1 and S2 software measurement standards for software calibration of measuring instruments.

Standard (etalon) term definition.

--- Part 72. XML file format x3p. The purpose is to specify XML files for storing and exchanging shape and contour data

Format x3p.

--- Part 601. Nominal characteristics of contact (stylus) instruments. The purpose is to specify the surface structure area method contact (stylus) type instrument

Nominal characteristics of the device.

--- Part 602. Nominal characteristics of non-contact (confocal chromatic aberration probe) instruments. The purpose is to specify the use of axial

Design and metrological characterization of a non-contact instrument for measuring surface structure with a confocal chromatic aberration probe for dispersion properties.

--- Part 603. Nominal characteristics of non-contact (phase-shift interference microscopy) instruments. The purpose is to specify the phase-shift interferometry (PSI) profile and metrological properties of area surface structure measurement microscopes.

--- Part 604. Nominal characteristics of non-contact (coherent scanning interference) type instruments. The purpose is to specify the surface height three-dimensional mapping

Metrology characteristics of a coherent scanning interferometry (CSI) measurement system for radiation.

--- Part 605. Nominal characteristics of non-contact (point AF probe) instruments. The purpose is to specify the use of point AF probes

Metrological properties of non-contact instruments for measuring surface structures.

--- Part 606. Nominal characteristics of non-contact (zoom) instruments. The purpose is to specify the use of variable focus (FV) sensors to measure surfaces